

[0209] The RAID storage system 2000 may include the RAID controller 2500. The RAID controller 2500 may include the RAID controller 100 of FIG. 6. The RAID controller 2500 may operate according to at least some example embodiments of the inventive concepts described with reference to FIGS. 7 through 17.

[0210] For example, the RAID controller 2500 may manage information of ECC result indicators, based on results of ECC decoding operations received from the ECC circuits 2111a, 2111b, and 2111c. The RAID controller 2500 may recover a data chunk that includes ECC unit data having an uncorrectable ECC error, with reference to the ECC result indicators. The RAID controller 2500 may provide a host with a stripe including the recovered data chunk. For brevity, some redundant descriptions will be omitted from the description of FIG. 18.

[0211] As illustrated in FIG. 18, the RAID controller 2500 may be implemented in an independent circuit or device. Alternatively, some or all of functions of the RAID controller 2500 may be included in the central controller 2300, or may be distributed to the device controllers 2110a, 2110b, and 2110c.

[0212] The RAID controller 2500 may support a multi-channel communication according to the number of the storage devices 2100a, 2100b, and 2100c. According to at least some example embodiments of the inventive concepts, the RAID controller 2500 may be implemented by separate circuits or devices as much as the number of the storage devices 2100a, 2100b, and 2100c. According to at least some example embodiments of the inventive concepts, the ECC circuits 2111a, 2111b, and 2111c may be implemented in one circuit or device, and thus may be configured to correspond to one RAID controller 2500.

[0213] As described above, the RAID controller 2500 may include several memory regions. However, according to at least some example embodiments of the inventive concepts, the RAID controller 2500 may share a memory region of the host and/or the storage devices 2100a, 2100b, and 2100c. At least some example embodiments of the inventive concepts may be variously changed or modified.

[0214] FIG. 19 is a block diagram illustrating a storage device that includes a RAID controller in accordance with at least some example embodiments of the inventive concepts.

[0215] According to at least some example embodiments of the inventive concepts, the RAID storage device 1200 of FIG. 1 may be implemented in one storage device 3000. The storage device 3000 may include a plurality of nonvolatile memory devices 3100. The nonvolatile memory devices 3100 may dispersively store a plurality of data chunks and a parity included in one stripe. The nonvolatile memory devices 3100 may include a nonvolatile memory examples of which include, but are not limited to, a flash memory, a PRAM, a ReRAM, a MRAM, and/or a FRAM.

[0216] The storage device 3000 may include a device controller 3300. The device controller 3300 may control the overall operations of the storage device 3000. For example, the device controller 3300 may include one or more ECC circuits 3310. The ECC circuits 3310 may perform ECC decoding operations on a plurality of ECC unit data included in the stored data chunk(s).

[0217] The device controller 3300 may include the RAID controller 3330. The RAID controller 3330 may include the RAID controller 100 of FIG. 6. The RAID controller 3330

may operate according to at least some example embodiments of the inventive concepts described with reference to FIGS. 7 through 17.

[0218] For example, The RAID controller 3330 may manage information of ECC result indicators, based on results of ECC decoding operations received from the ECC circuits 3310. The RAID controller 3330 may recover a data chunk that includes ECC unit data having an uncorrectable ECC error, with reference to the ECC result indicators. The RAID controller 3330 may provide a host with a stripe including the recovered data chunk. For brevity, redundant descriptions will be omitted.

[0219] As illustrated in FIG. 19, the RAID controller 3330 may be included in the device controller 3300. Alternatively, the RAID controller 3330 may be configured separately from the device controller 3300, or may be configured separately from the storage device 3000.

[0220] The RAID controller 3330 may support a multi-channel communication according to the number of the nonvolatile memory devices 3100. According to at least some example embodiments of the inventive concepts, the RAID controller 3330 may be implemented by separate circuits as much as the number of the nonvolatile memory devices 3100. According to at least some example embodiments of the inventive concepts, the ECC circuits 3310 may be implemented by separate circuits as much as the number of channels being supported by the RAID controller 3330 or as much as the number of the nonvolatile memory devices 3100.

[0221] As described above, the RAID controller 3330 may include several memory regions. However, According to at least some example embodiments of the inventive concepts, the RAID controller 3330 may share a memory region of the host, the device controller 3300, and/or the storage device 3000. At least some example embodiments of the inventive concepts may be variously changed or modified.

[0222] According to at least some example embodiments of the inventive concepts, a data chunk including an uncorrectable error may be recovered. Thus, the RAID storage system or the storage device may guarantee high reliability of data. Furthermore, the RAID storage controller may not require additional parity to recover a data chunk. Thus, the overhead of the RAID storage system or the storage device may not greatly increase.

[0223] Circuits, chips, and devices according to at least some example embodiments of the inventive concepts may be mounted using various kinds of semiconductor packages. For example, circuits, chips, and devices according to at least some example embodiments of the inventive concepts may be mounted using a package such as package on package (PoP), ball grid arrays (BGAs), chip scale packages (CSPs), plastic leaded chip carrier (PLCC), plastic dual in-line package (PDIP), die in wafer pack, die in wafer form, chip on board (COB), ceramic dual in-line package (CERDIP), metric quad flat pack (MQFP), small outline integrated circuit (SOIC), shrink small outline package (SSOP), thin small outline package (TSOP), thin quad flat pack (TQFP), system in package (SIP), multi-chip package (MCP), wafer-level fabricated package (WFP), and/or wafer-level processed stack package (WSP).

[0224] Example embodiments of the inventive concepts having thus been described, it will be obvious that the same may be varied in many ways. Such variations are not to be regarded as a departure from the intended spirit and scope of